

OPERATION OF A LOW-VOLTAGE HIGH-TRANSCONDUCTANCE FILED EMITTER ARRAY TWT (BRIEFING CHARTS)

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CONFERENCE BRIEFING CHARTS

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Operation of a Low-Voltage High-Transconductance Field Emitter Array TWT

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Introduction



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- Implementation of “cold cathodes” as an electron source for RF vacuum devices can have a significant impact on many aspects of device operation

Cold Cathode Impact on RF Device Operation

- No Cathode Wearout Mechanism
- Multi-Mode Operation
- Room Temperature Operation
- Infinite ON/OFF Isolation
- Eliminate Heater Power
- Device Miniaturization[†]
- High Current Density Operation
- Increased Interaction Efficiency[†]
- Instant Turn-on
- Improved Linearity[†]
- Eliminate HV Modulator
- Decreased Harmonic Power[†]

Introduction

Cold Cathode TWT History

- NEC Corporation
 - Late 1990s
 - Replaced thermionic cathode in X-Band TWT with Spindt-type cold cathode
 - 58 mA, 27.5 W, 10.5 GHz, 3% duty max (limited by TWT vacuum)
 - Focusing difficulties in first prototype – subsequently resolved
 - No recent activity
- Northrop Grumman Corporation
 - 1999 – 2002
 - C-Band cold cathode TWT
 - Single pulse up to 91 mA, 55 W, 4.5 GHz
 - 1% maximum duty factor at lower currents
 - 2002
 - RF-modulated cold cathode TWT
 - 5mA, 280mW, 6.75 GHz
 - No recent activity
- L-3 Communications – Electron Devices
 - 2007
 - C-Band cold cathode TWT
 - 30 mA, 18 W, 4.1 GHz, 1% duty
 - 10% duty at 10mA
 - 6 hrs lifetest at 1% duty, 2 hrs lifetest at 10% duty



Introduction



L-3 Electron Devices Cold Cathode TWT Program

- Field emitter arrays have undergone a significant evolution in past several years, substantially reducing required operating voltages and potentially increasing life and reliability
- L-3 EDD has established a Vacuum Microelectronics Laboratory for testing of Cold Cathode Vacuum Devices
- A Field Emitter Array TWT test vehicle has been designed, fabricated and tested to evaluate the characteristics of the new low-voltage FEA cathodes and to characterize/optimize FEA TWT performance

Introduction



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- Progress To Date

- Built laboratory, integrated equipment and control system
- Designed and fabricated electron gun capable of controlling high current density FEA electron beam
- Integrated FEA cathode into TWT electron gun
- Designed and fabricated TWT circuit/magnetics for
 - excellent beam control
 - high efficiency
 - wide bandwidth
 - moderate gain
- Built prototype cold cathode TWT
- Demonstrated performance exceeding all past measures of performance including beam current, cathode current density, total run time, duty factor, RF peak power, RF average power
- Performed life tests, cold cathode processing in TWT environment, noise measurements

Simulation

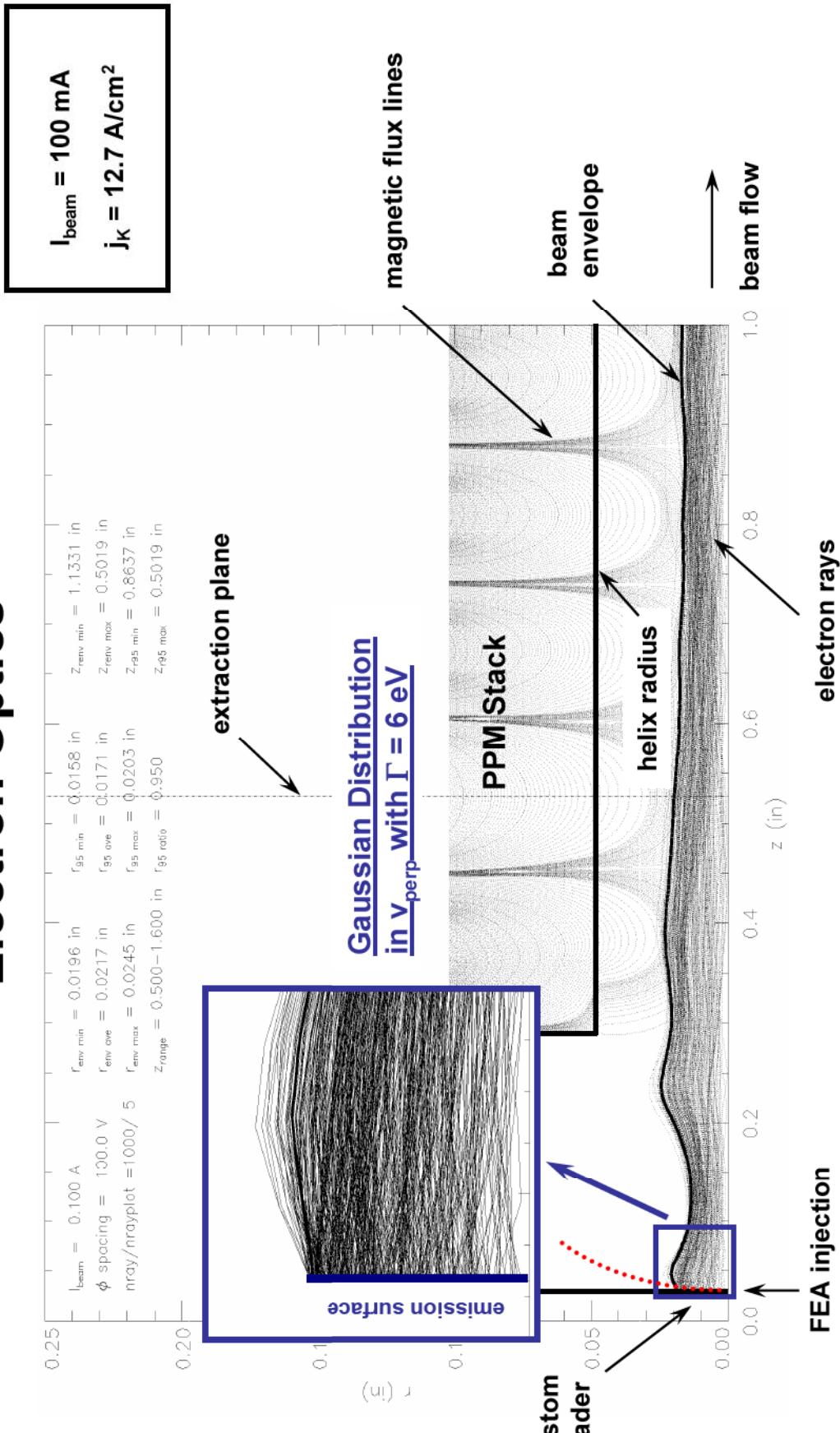


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Electron Optics

$I_{beam} = 0.100 \text{ A}$
 $\phi_{\text{spacing}} = 130.0 \text{ V}$
 $n_{ray}/n_{rayplot} = 1000/5$
 $r_{env} = 0.500 - 1.600 \text{ in}$
 $r_{env \text{ min}} = 0.0196 \text{ in}$
 $r_{env \text{ ave}} = 0.0217 \text{ in}$
 $r_{env \text{ max}} = 0.0245 \text{ in}$
 $r_{95 \text{ min}} = 0.0158 \text{ in}$
 $r_{95 \text{ ave}} = 0.0171 \text{ in}$
 $r_{95 \text{ max}} = 0.0203 \text{ in}$
 $Z_{env \text{ min}} = 1.1331 \text{ in}$
 $Z_{env \text{ ave}} = 0.5019 \text{ in}$
 $Z_{env \text{ max}} = 0.8637 \text{ in}$
 $Z_{95 \text{ min}} = 0.8637 \text{ in}$
 $Z_{95 \text{ ave}} = 0.5019 \text{ in}$
 $Z_{95 \text{ max}} = 0.950 \text{ in}$
 $r_{95 \text{ ratio}} = 0.950$

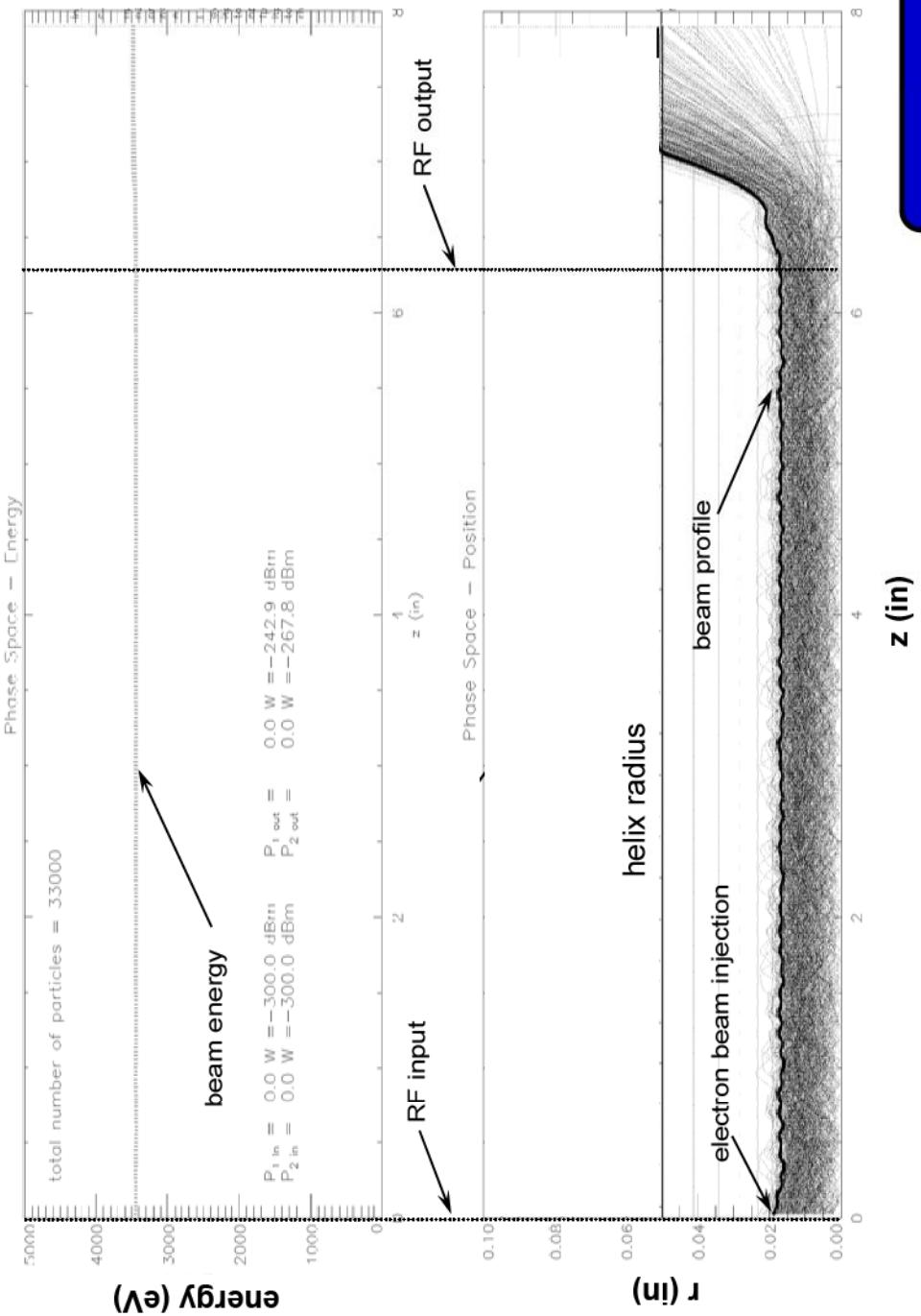


Simulation



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CHRISTINE3D Interaction Simulation – No RF Drive



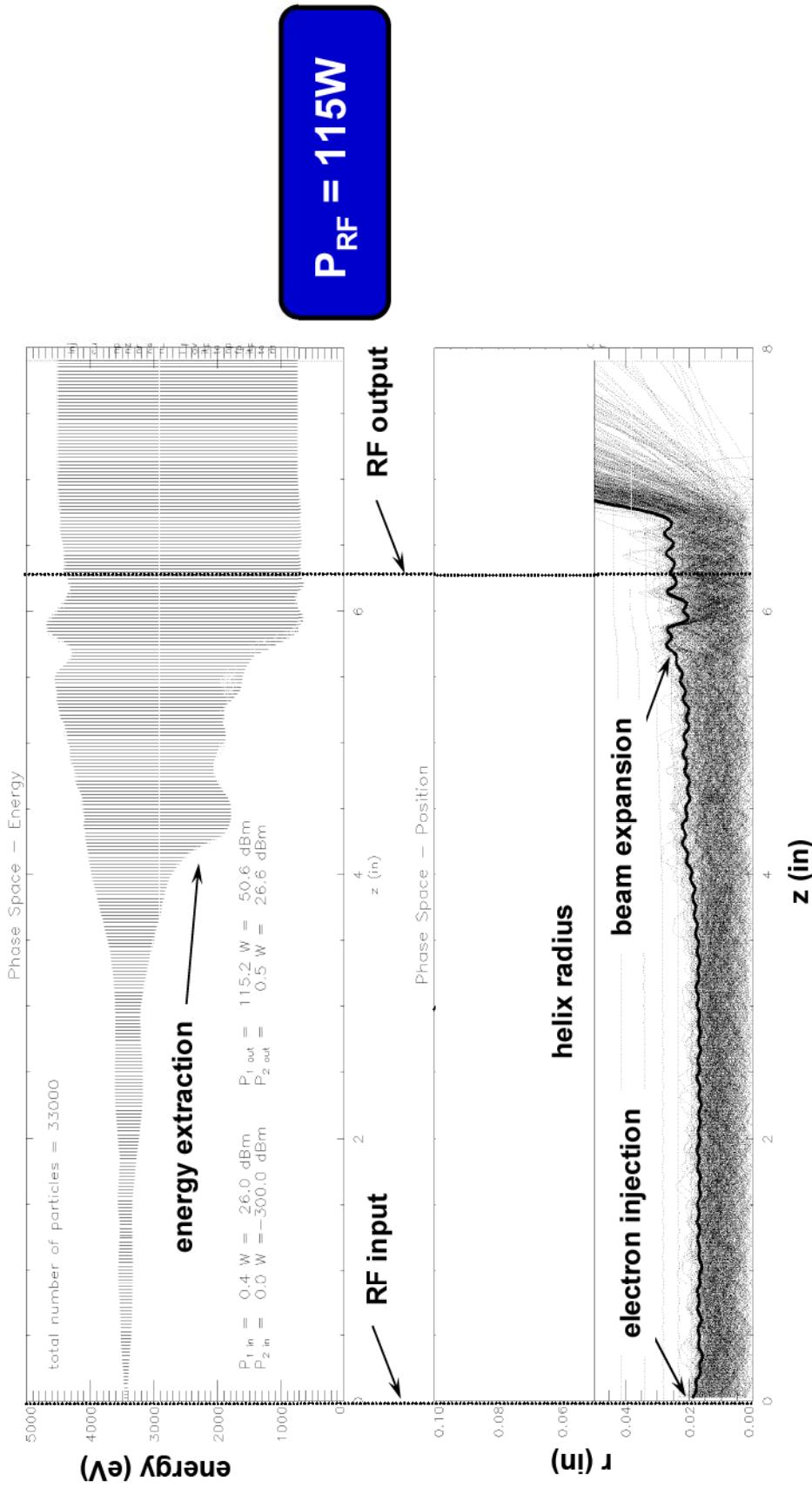
Simulation



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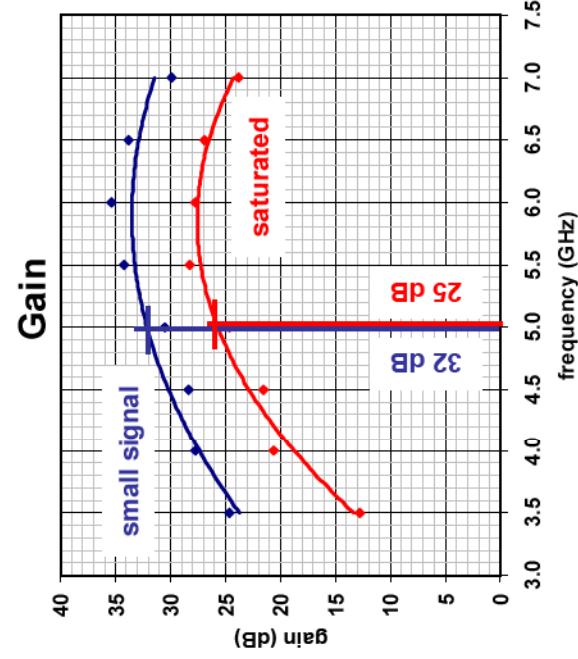
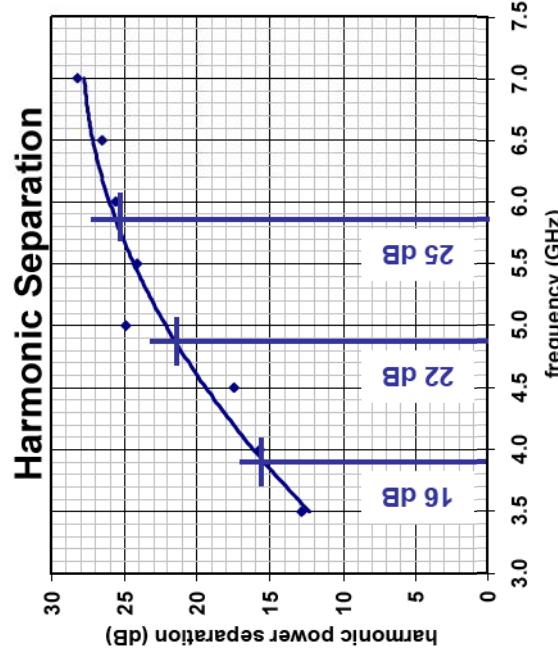
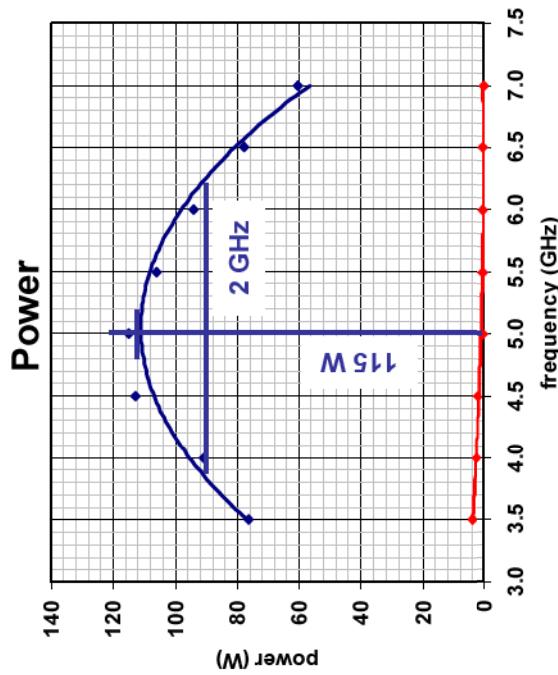
CHRISTINE3D Interaction Simulation – Saturated, Band Center



Simulation



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I_{beam}	100 mA
V_{beam}	3500 V
Sat Power	115 W
SS Gain	32 dB
Sat Gain	25 dB
$\eta_{circuit}$	32 %
1 dB B/W	2 GHz
3 dB B/W	4 GHz

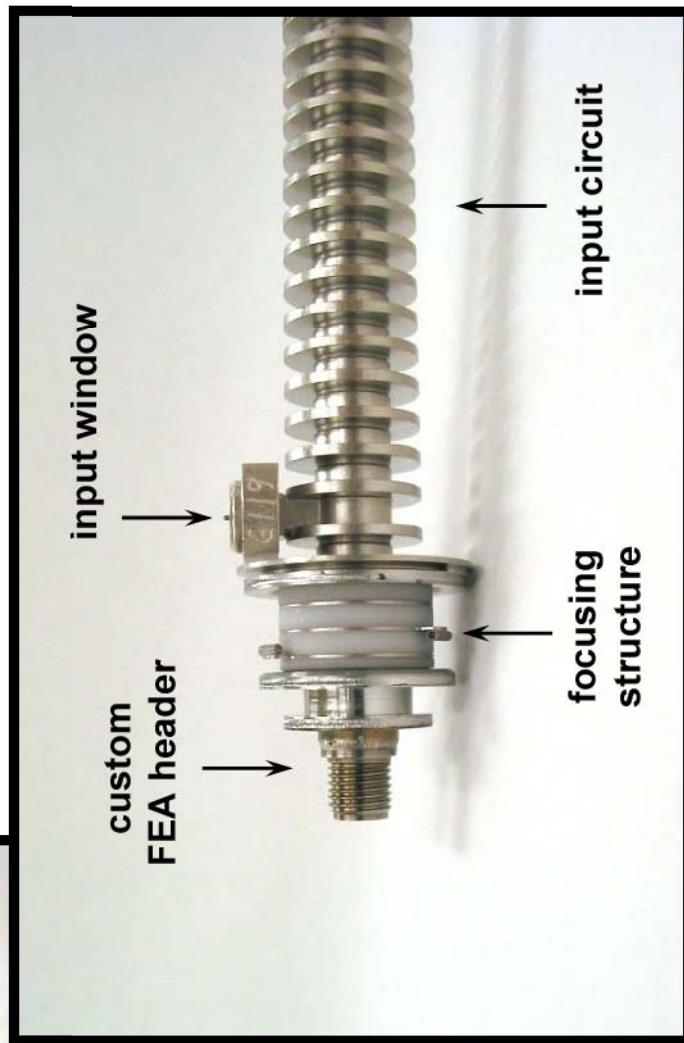
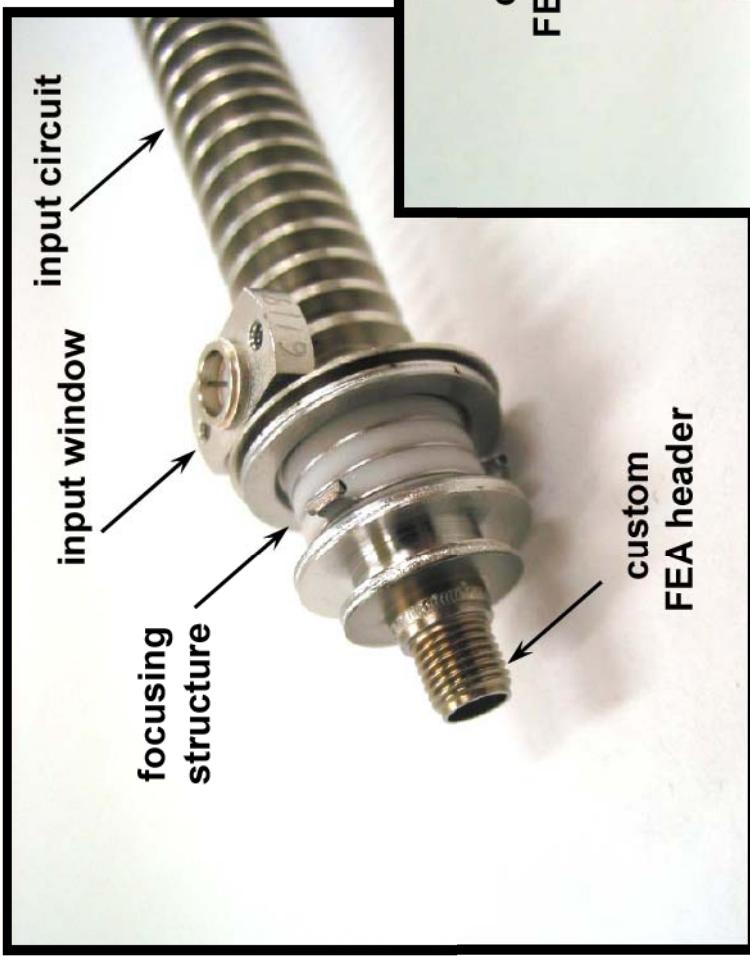
Hardware



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Prototype #1 – Pre-Exhaust



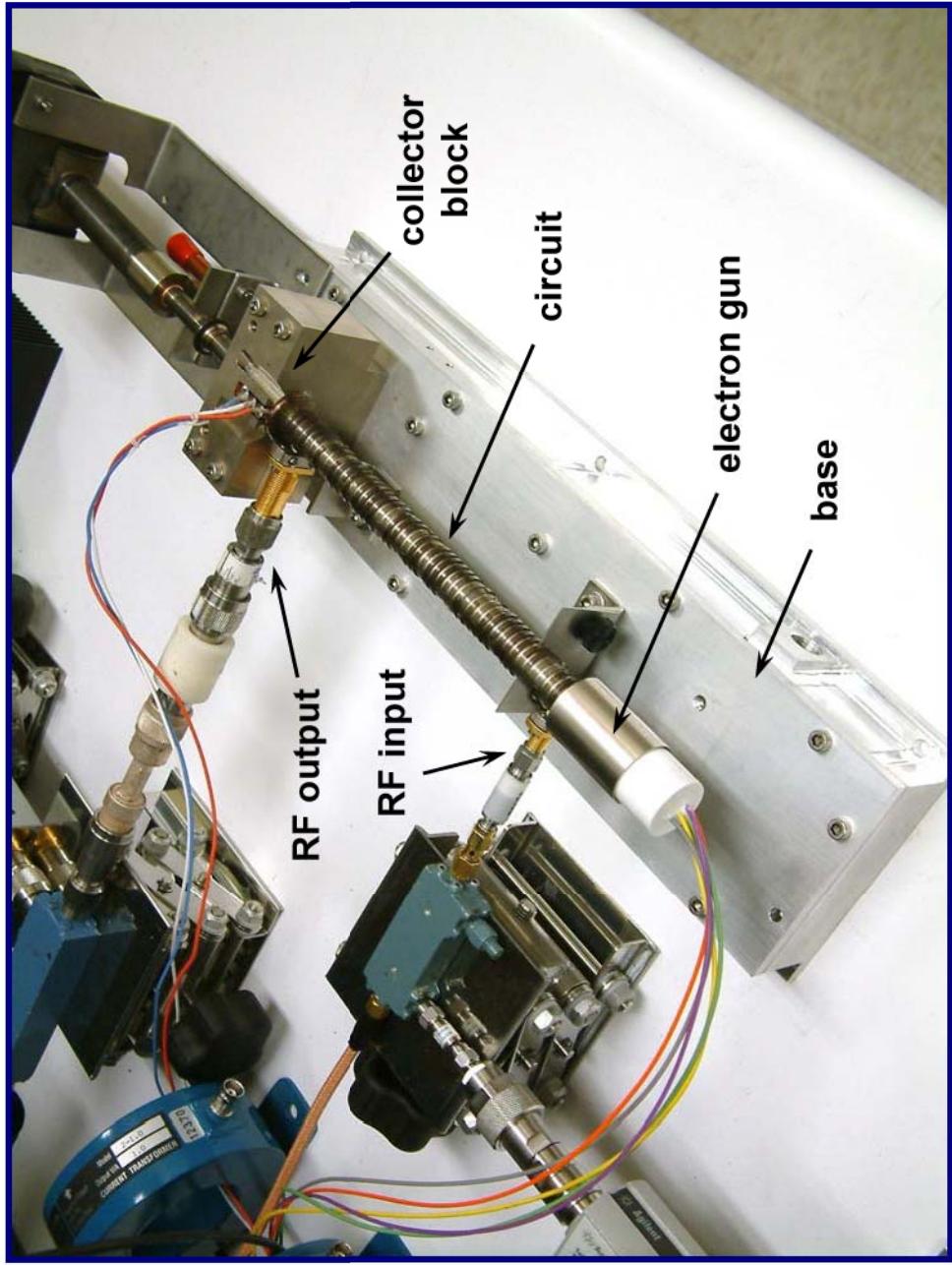
Hardware



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Final Experimental Configuration – Prototype #1



SRI Emitter Characteristics

diameter	1 mm
tip number	50,000
tip material	Molybdenum
a_{FN}	0.030 A/V ²
b_{FN}	490 V

Laboratory

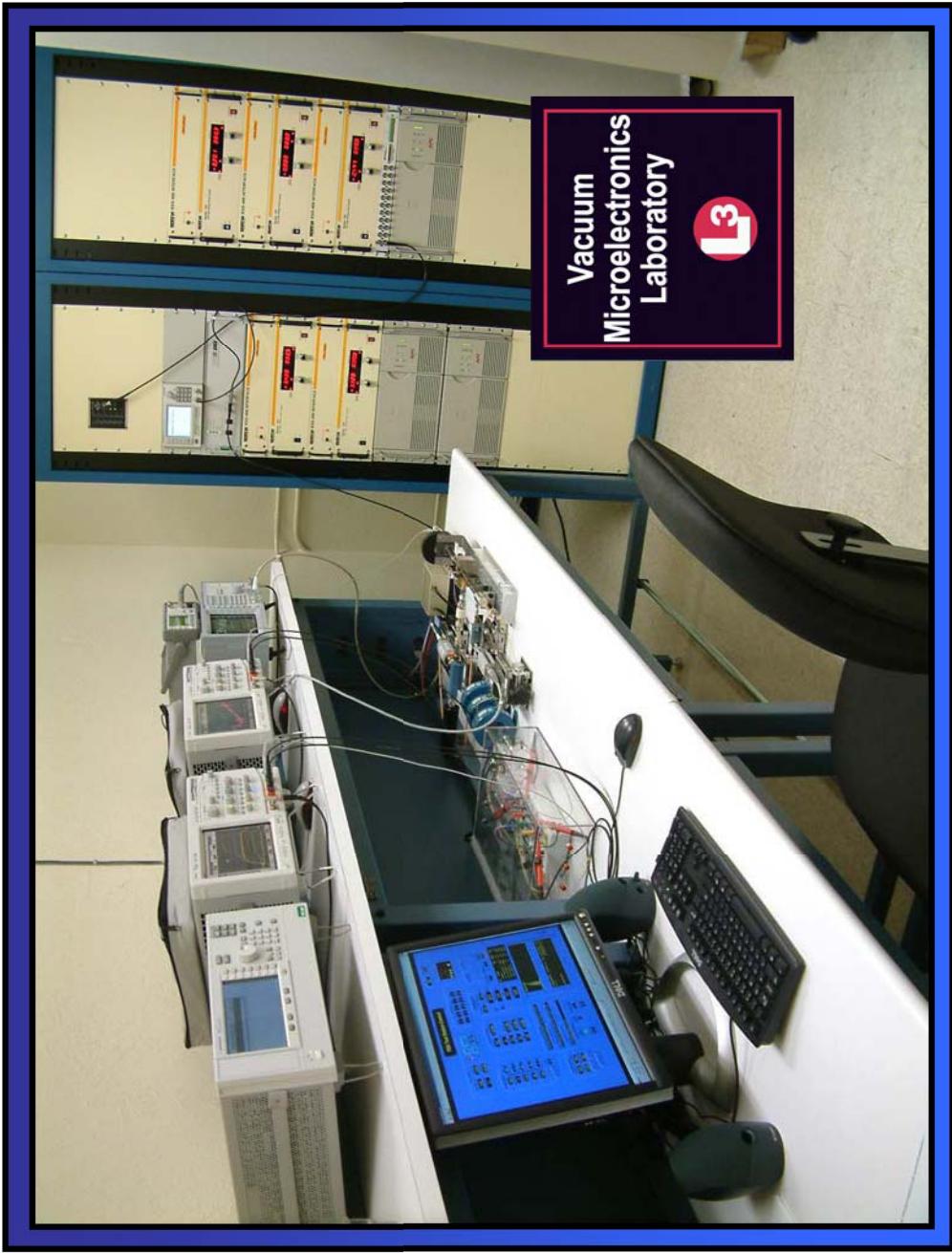


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Vacuum Microelectronics Laboratory

- Established for Test of Cold Cathode RF Vacuum Devices
- Dedicated Equipment
- Fully Functional
- Computer Controlled
- Life Test System Operational

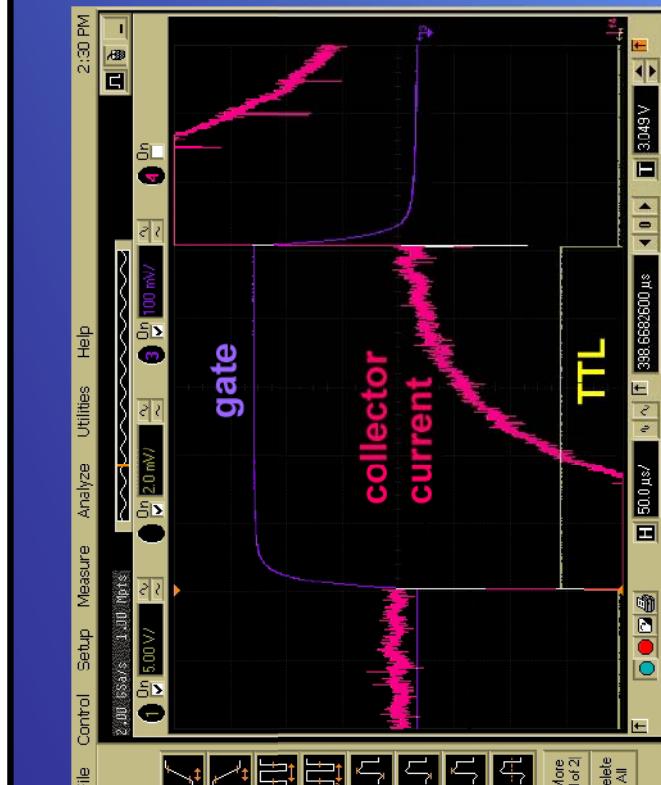


Experimental Results

Low Turn-on Voltage

$V_{\text{gate}} = 21 \text{ V}$

$V_{\text{gate}} = 23 \text{ V}$



FIRST MEASURED
FEA TWT CURRENT AT 23 V

$\uparrow = 1 \text{ nA}$



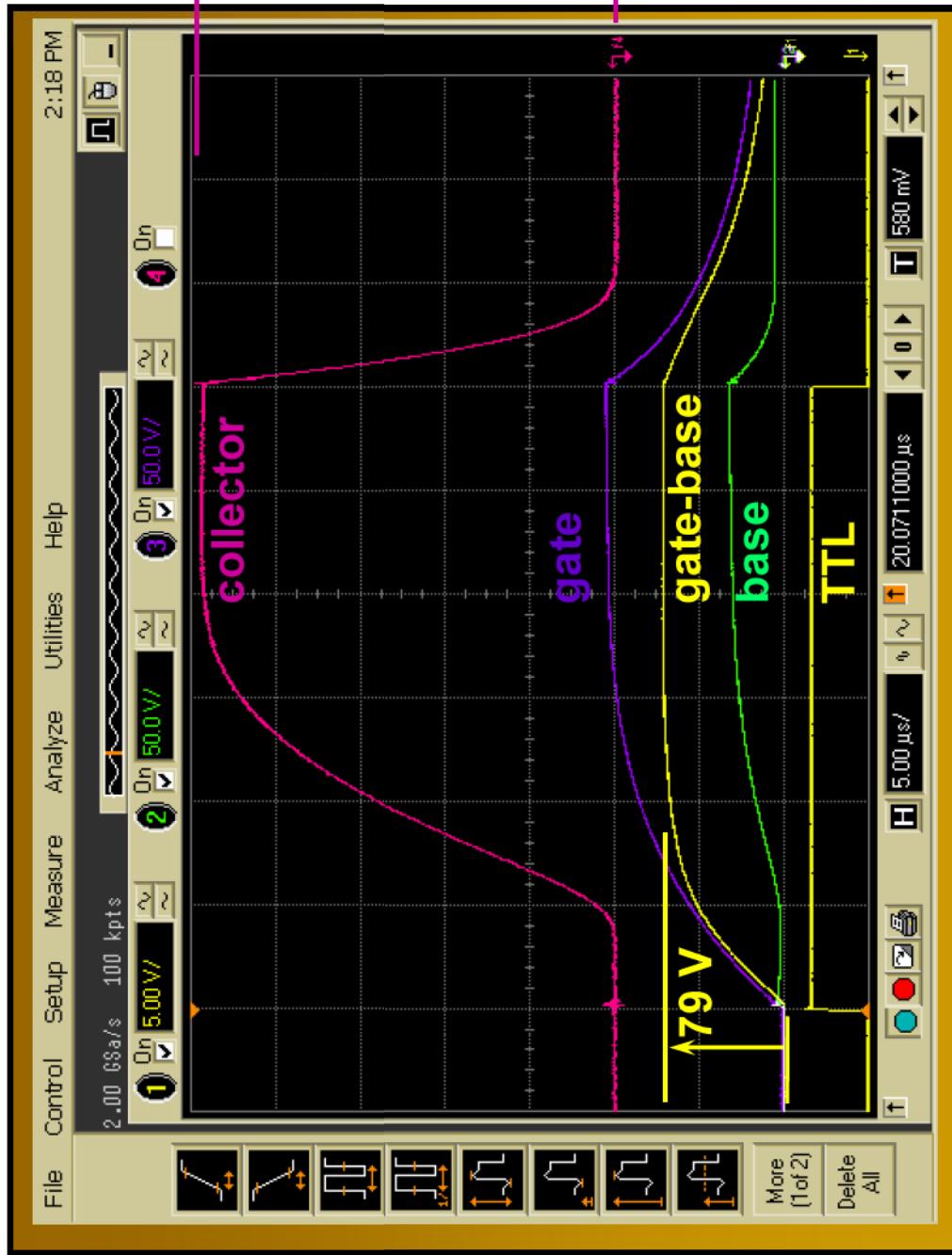
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Experimental Results

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Typical Waveforms



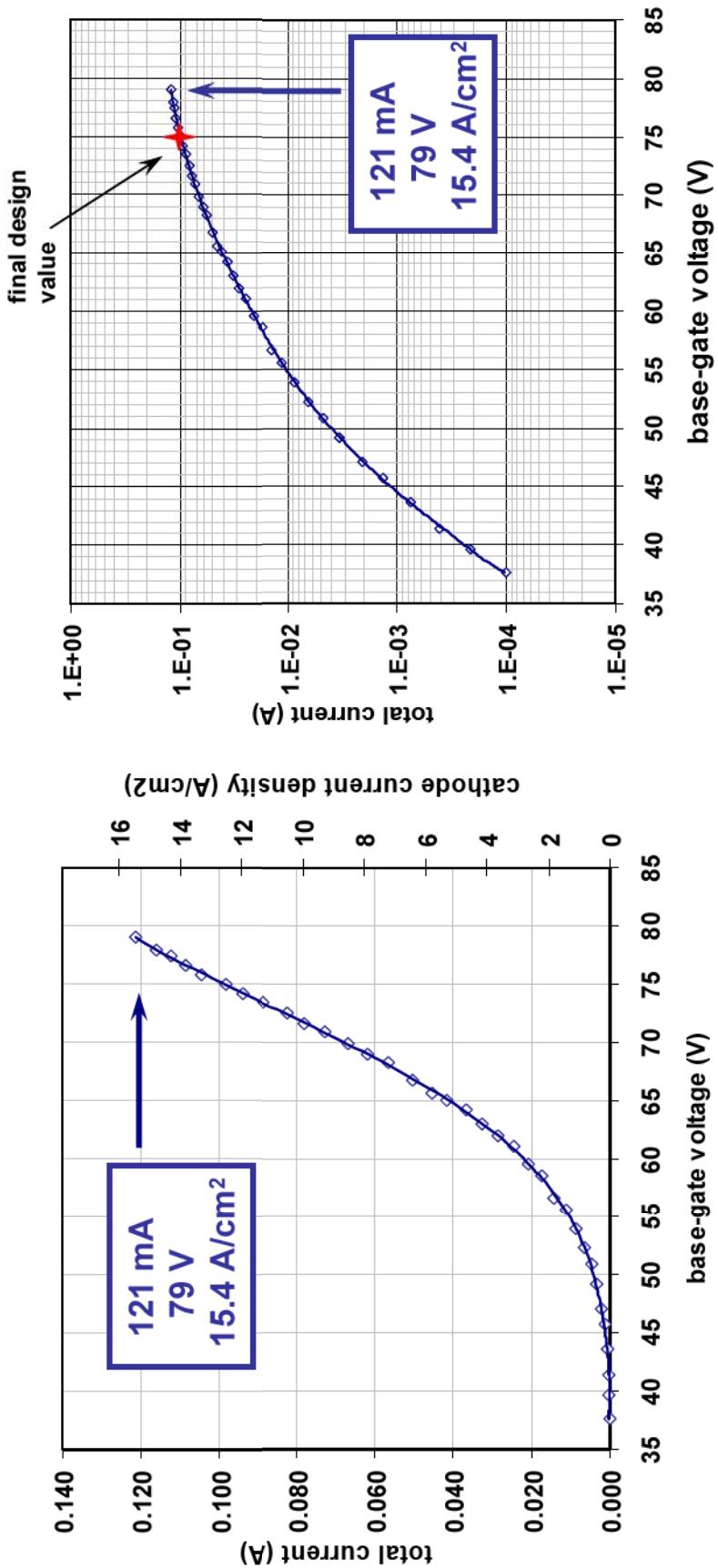
Experimental Results



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Measured FEA Emission vs. Base-Gate Voltage



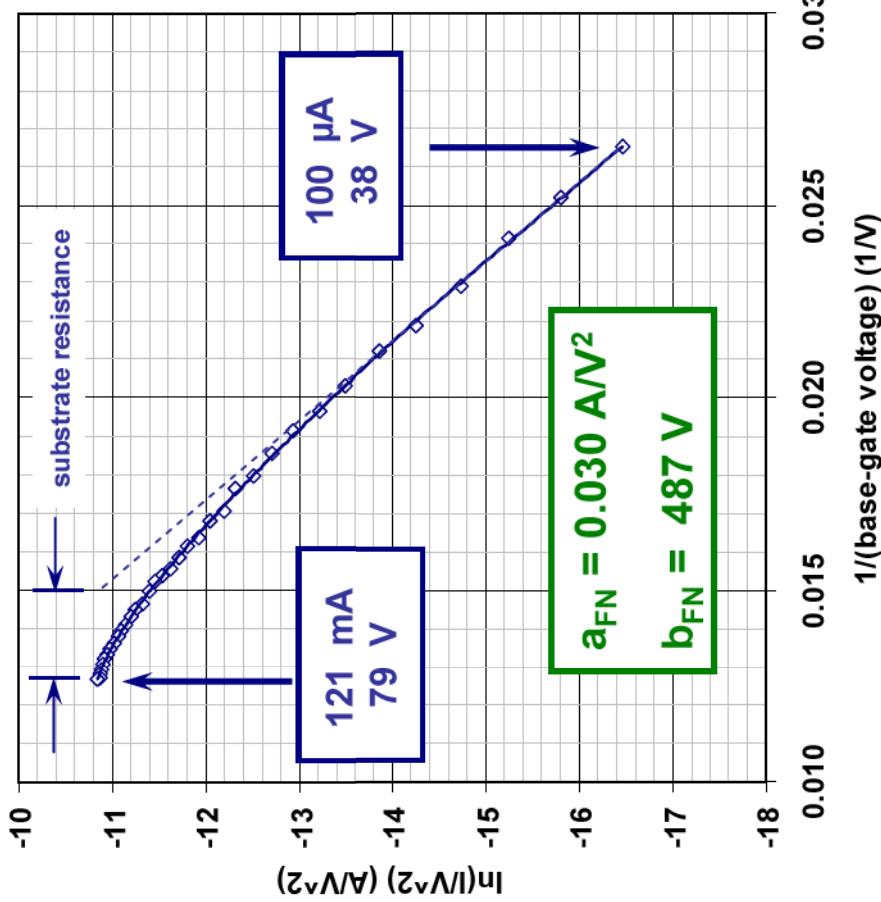
Experimental Results



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Fowler Nordheim Emission

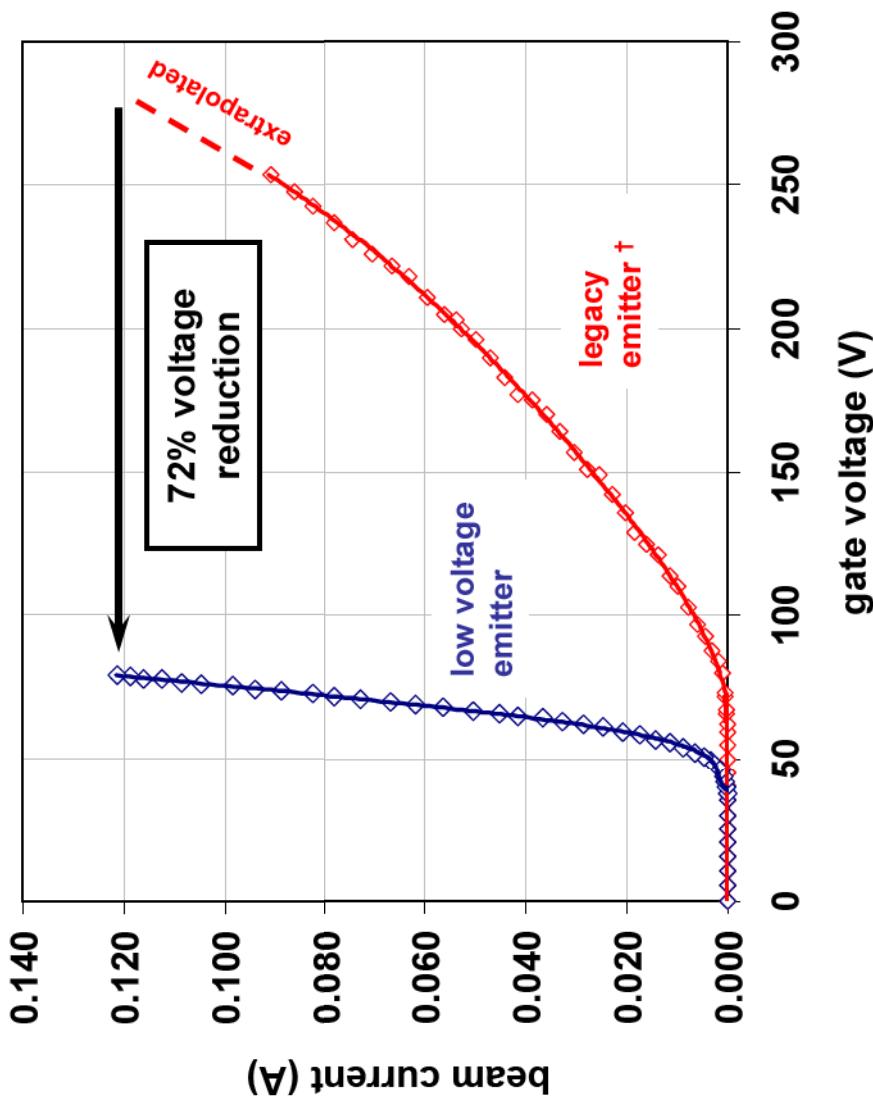


$$I = a_{FN} V_{BG}^2 \exp\left(-\frac{b_{FN}}{V_{BG}}\right)$$

$$\ln(I / V_{BG}^2) = \ln(a_{FN}) - \frac{b_{FN}}{V_{BG}}$$

Experimental Results

Operating-Voltage Reduction with New Low-Voltage Emitters



At maximum current

$$V_{\text{low voltage}} = 79 \text{ V}$$

$$V_{\text{legacy}} = 280 \text{ V}$$

$$\frac{V_{\text{low voltage}}}{V_{\text{legacy}}} = 0.28$$

† D. R. Whaley, et al., *IEEE Trans. on Plasma Science*, Vol. 28, No. 3, p. 727-747 (2000).

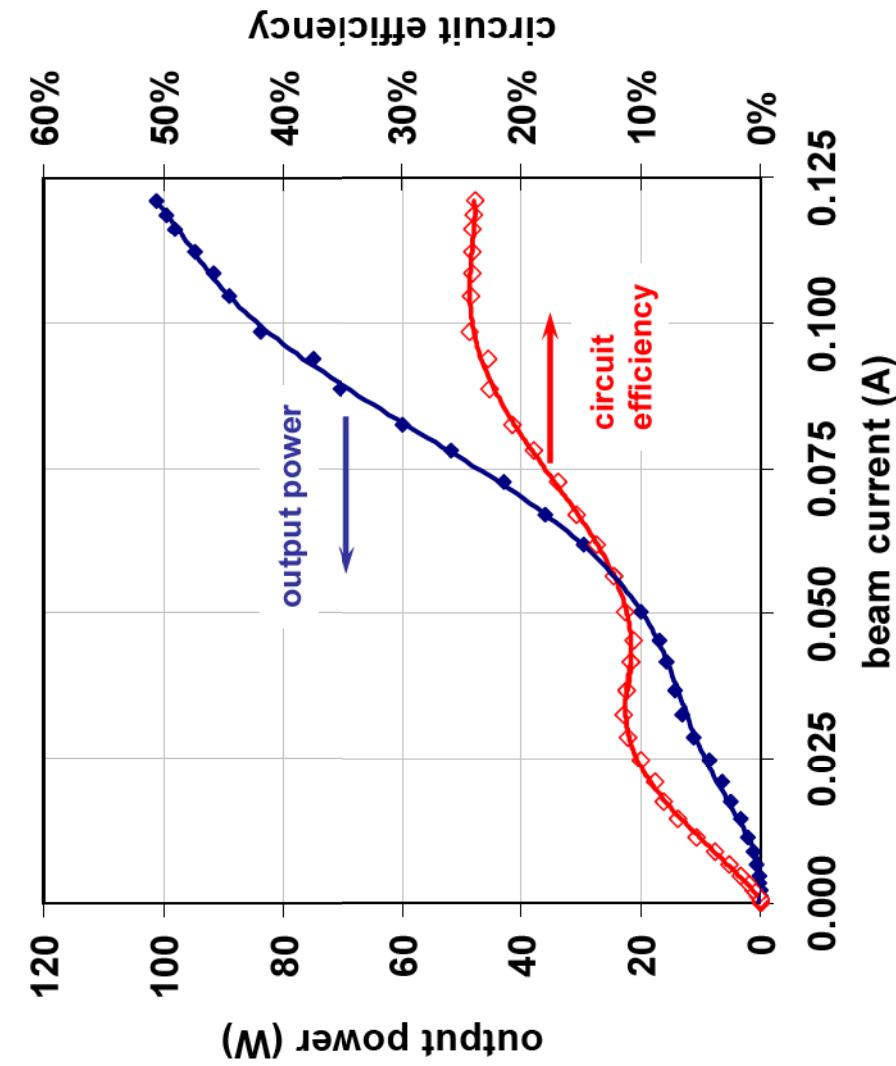
Experimental Results



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Output Power and Efficiency



At maximum current

V_{beam}	3500 V
I_{beam}	120 mA
Frequency	5.0 GHz
Small Signal Gain	32.7 dB
Sat Power	100 W
Sat Gain	22.1 dB
Circuit Efficiency	24 %

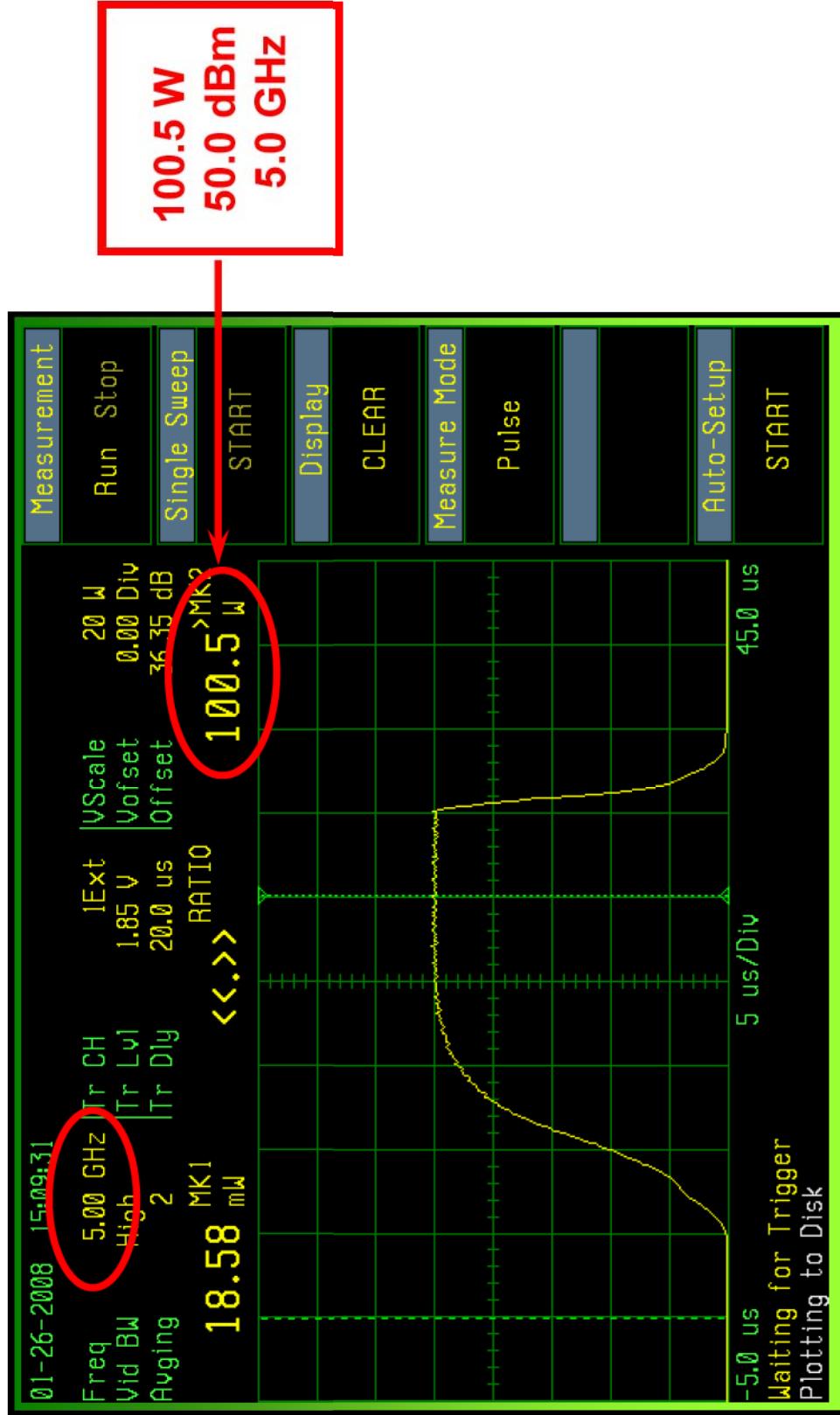
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Peak Power Analyzer – 120 mA



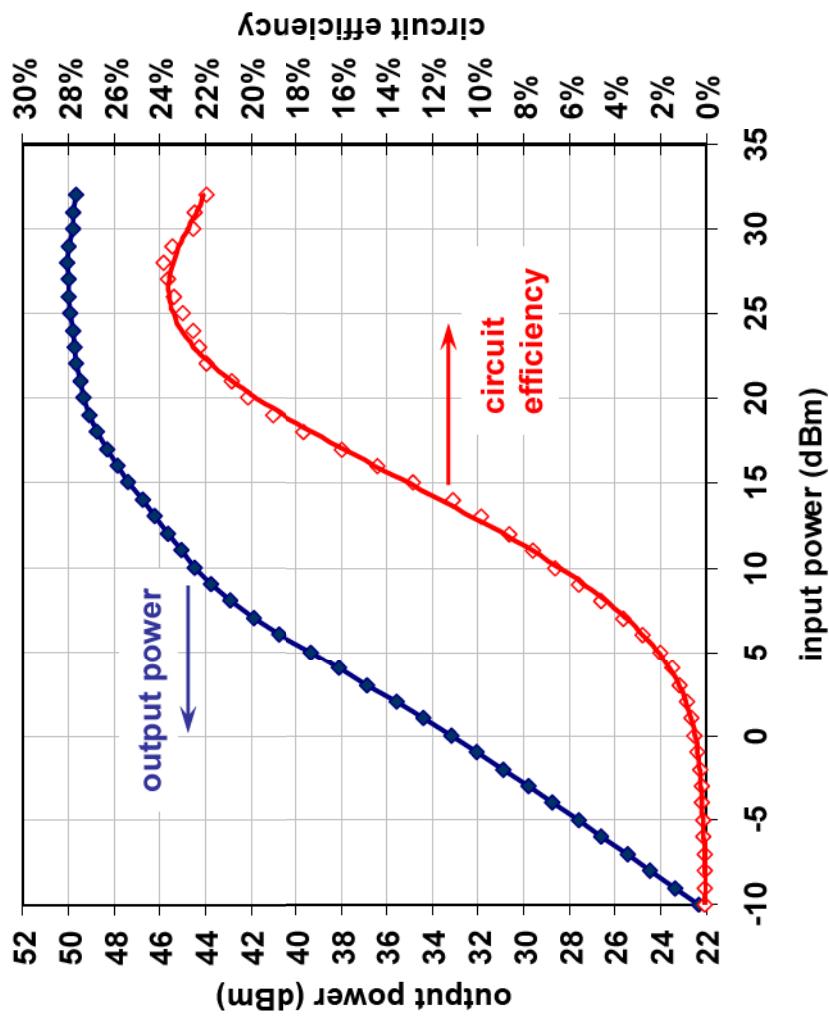
Experimental Results



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Drive Curve – 120 mA, 5GHz



V_{beam}	3500 V
I_{beam}	120 mA
Frequency	5.0 GHz
Small Signal Gain	32.7 dB
Sat Power	100 W
Sat Gain	22.1 dB
Max Circuit Efficiency	24 %

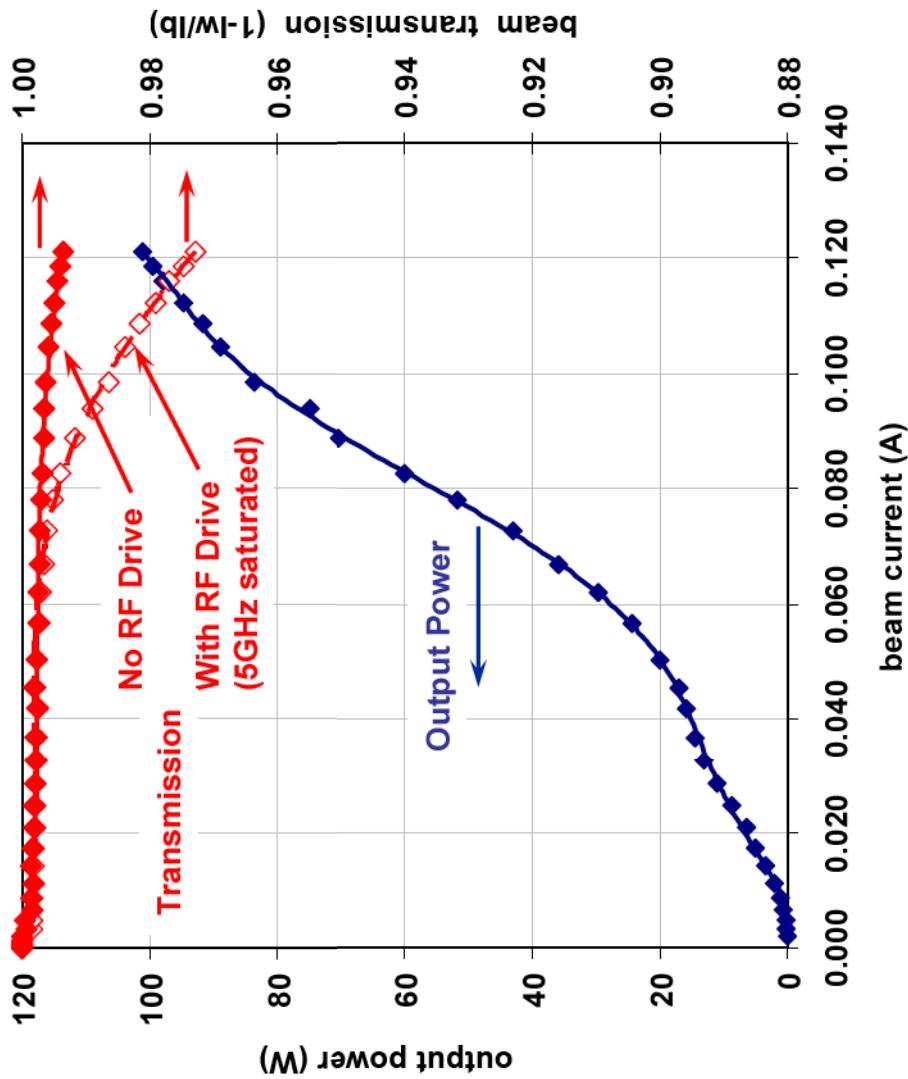
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FEA Beam Control



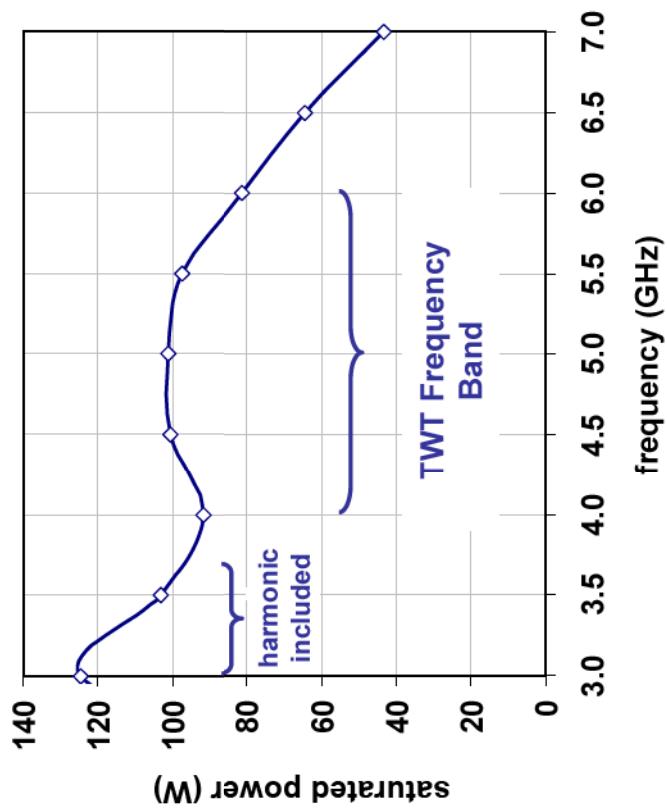
Beam Transmission
No RF Drive – 99.4%
Sat RF Drive – 97.3%

Experimental Results

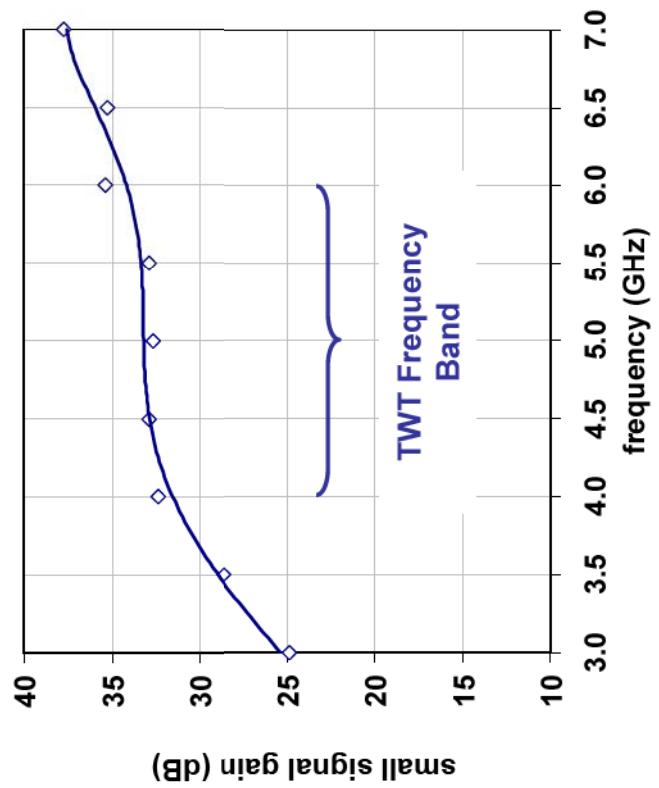


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Saturated Power



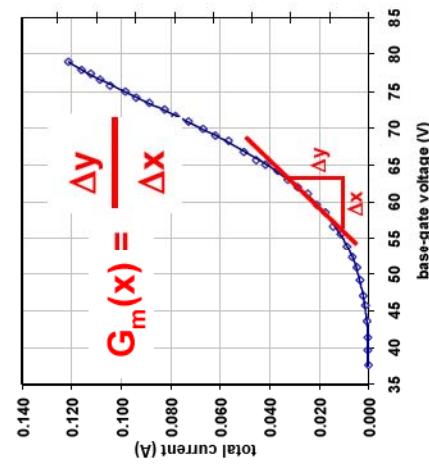
Small Signal Gain



Transconductance

- $G_m = dI/dV_{b-g}$
- Local slope of I/V curve
- Measure of current emission sensitivity to applied voltage
- Changes with applied voltage and emission current

- Measured in Siemens or A/V



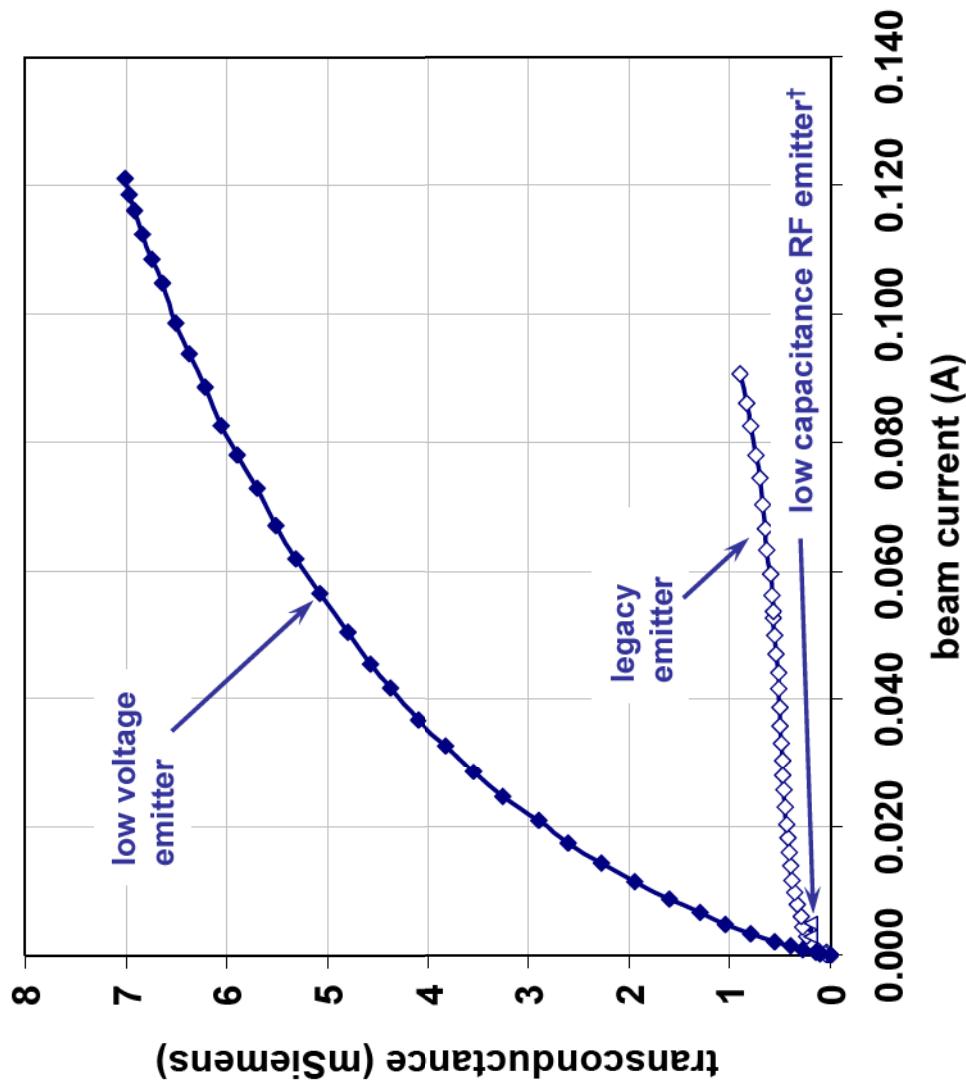
High Transconductance Cathodes

- Advantages
 - Generally means low turnon voltage and low operating voltage
 - Low cathode electrical stress
 - Low gate surge currents and gate heating during high PRF pulsed operation
 - RF-modulated operation possible
 - Offsets low capacitance requirement for RF modulated operation
- Disadvantages
 - Current emission sensitive to power supply drift
 - Power supply ripple can generate carrier sidebands due to unintended baseband current modulation

Experimental Results



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† D. R. Whaley, et al., *IEEE Trans. on Plasma Science*, Vol. 30, No. 3, p. 998-1008 (2002).

Experimental Results



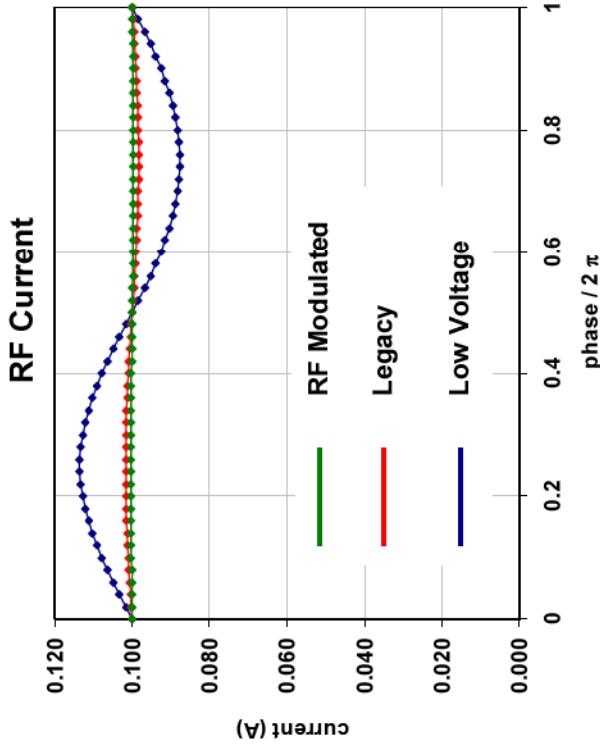
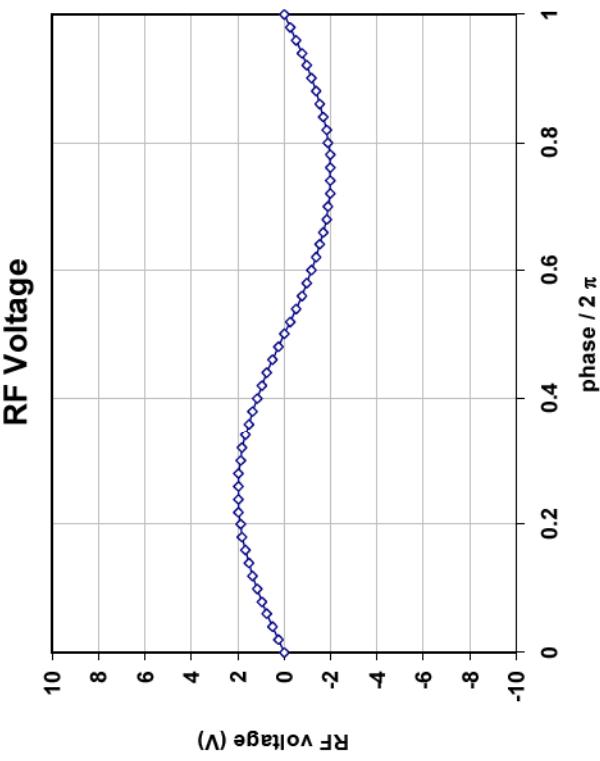
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- High Transconductance Can Offset Need for Low Capacitance in RF Modulated Cathodes

$$\text{Modulation Efficiency} = \frac{\Delta I_{RF}}{I} \propto \frac{\partial I}{\partial V} \times \Delta V_{RF}$$

transconductance $\frac{\partial I}{\partial V}$ inversely with capacitance



Experimental Results

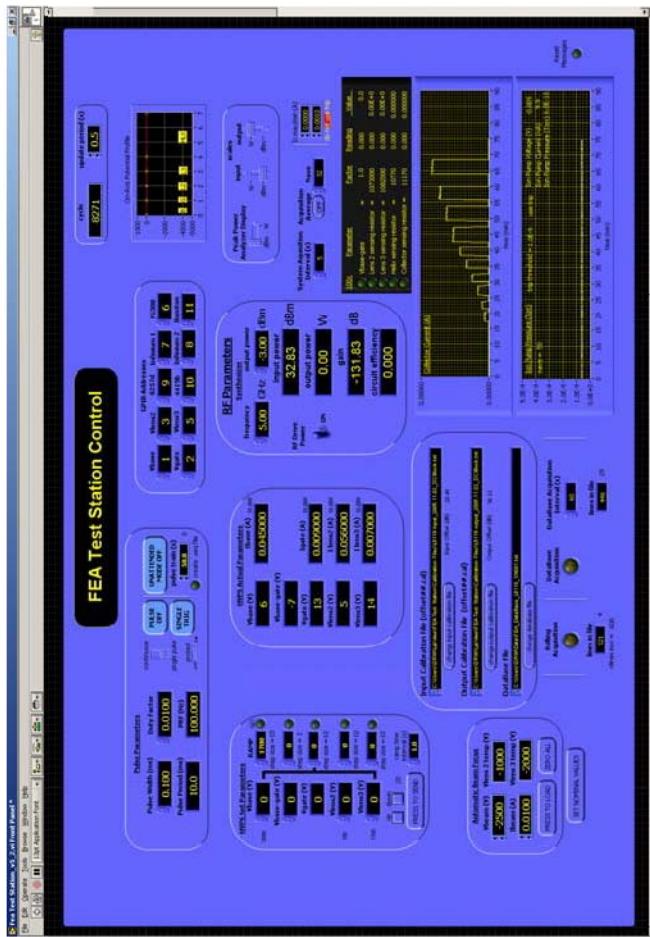


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Life Tests

- LabView data control and acquisition system records all TWT operating parameters vs. time

- time stamp
- pulse parameters (pulse width, duty factor)
- base voltage
- gate voltage
- gun lens voltages
- gun lens currents
- helix current
- collector current
- RF input power
- RF output power
- vacuum pressure



Experimental Results



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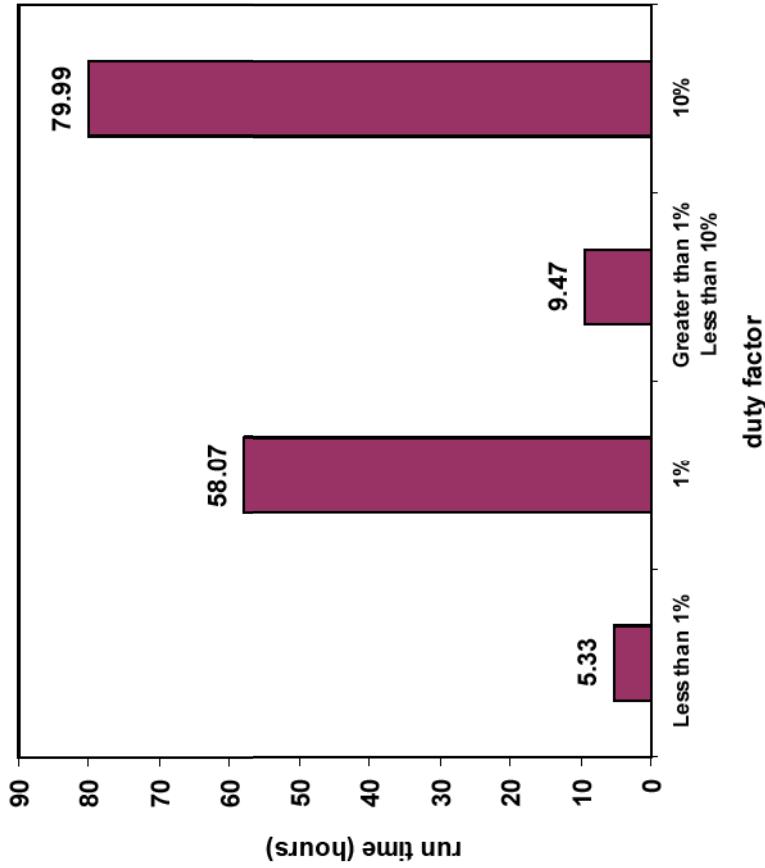
Life Test Summary

- 10% Duty Operation at 10mA, 20mA, 40mA, 60mA, and 80mA
- 1% Duty Operation at 100mA (85W)
- Single pulsing up to 120mA (100W)
- Total 1% Duty Pulse Time – 58 hours
- Total 10% Duty Pulse Time – 80 hours
- Total Pulse Time – 153 hours
- Total Number of Database Points – 56 k
- Total FEA Pulses – 826 M

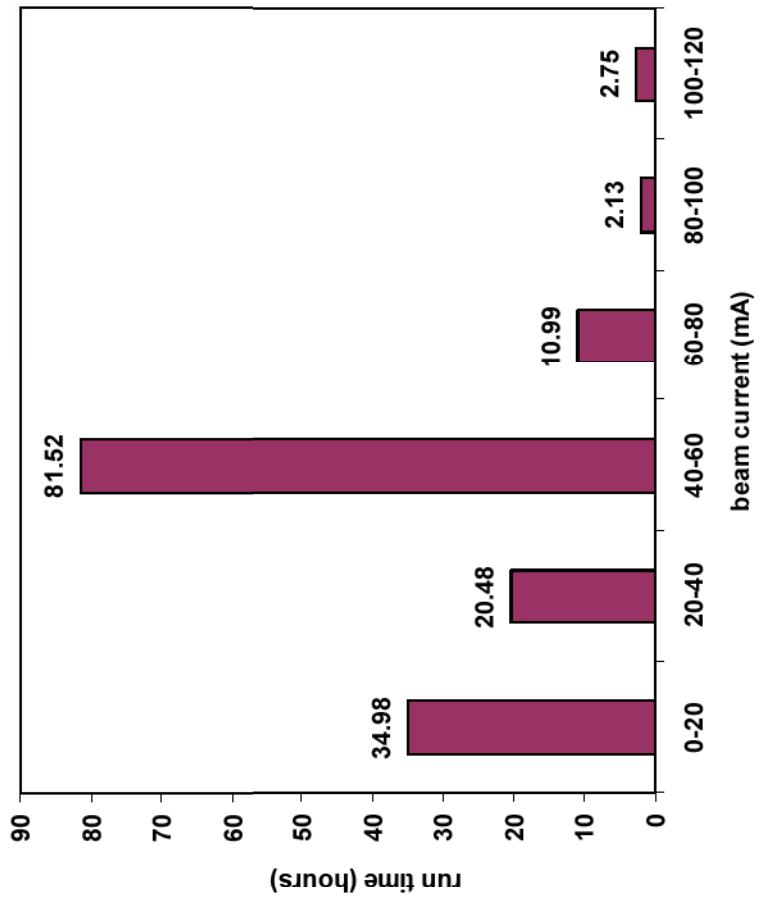
Experimental Results



Duty Factor



Beam Current (Peak)

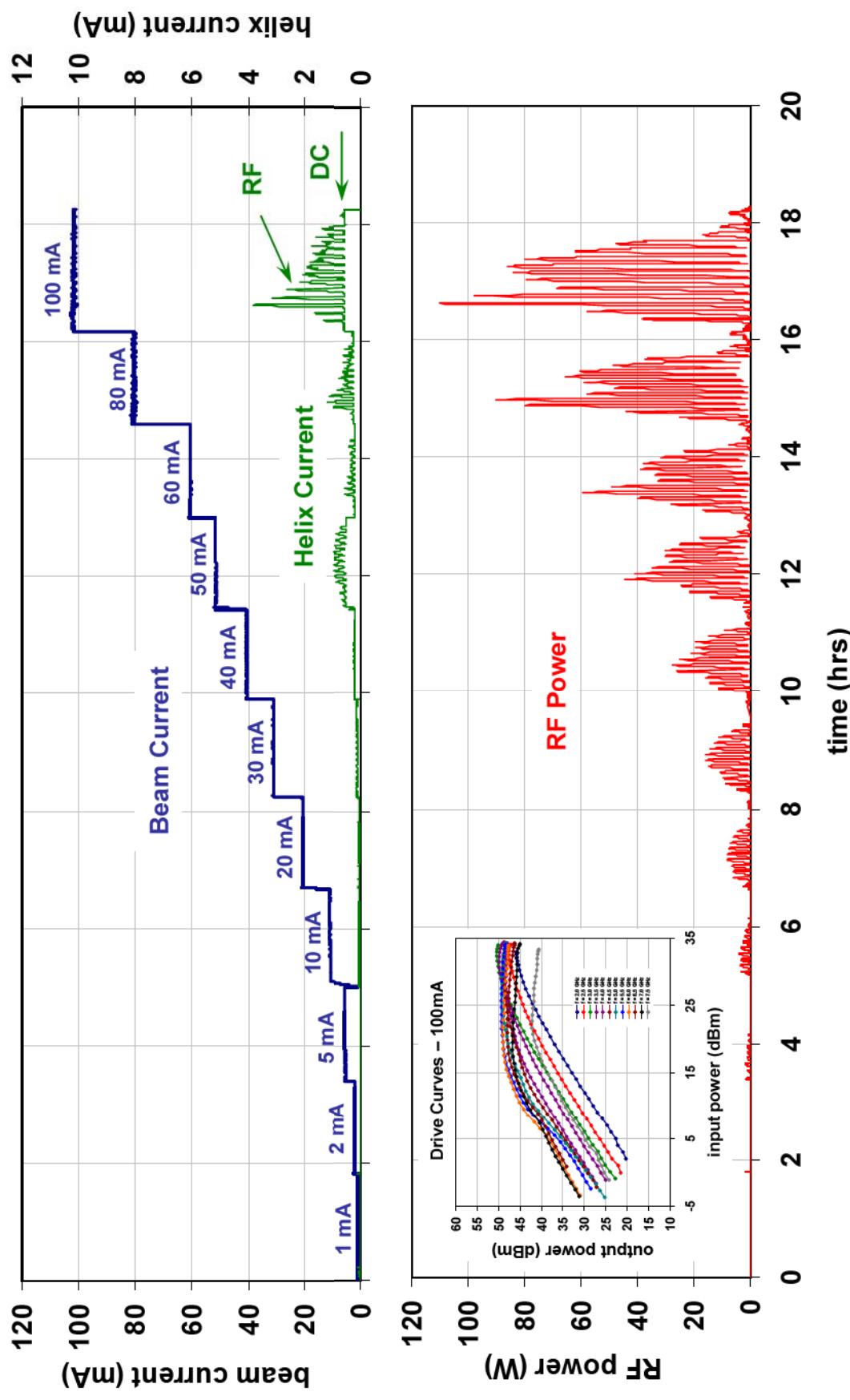


Experimental Results

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Device Characterization



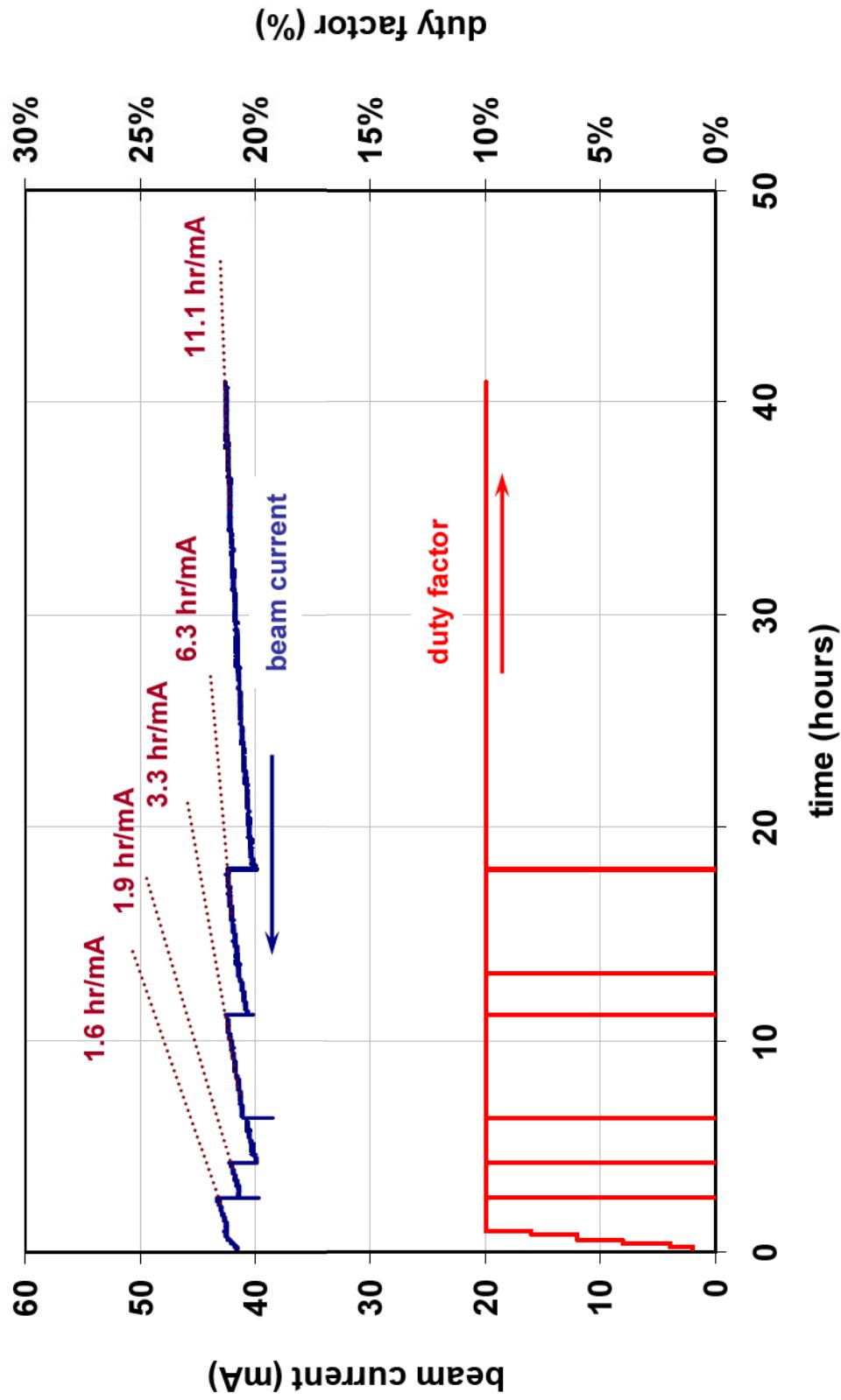
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High Duty Processing



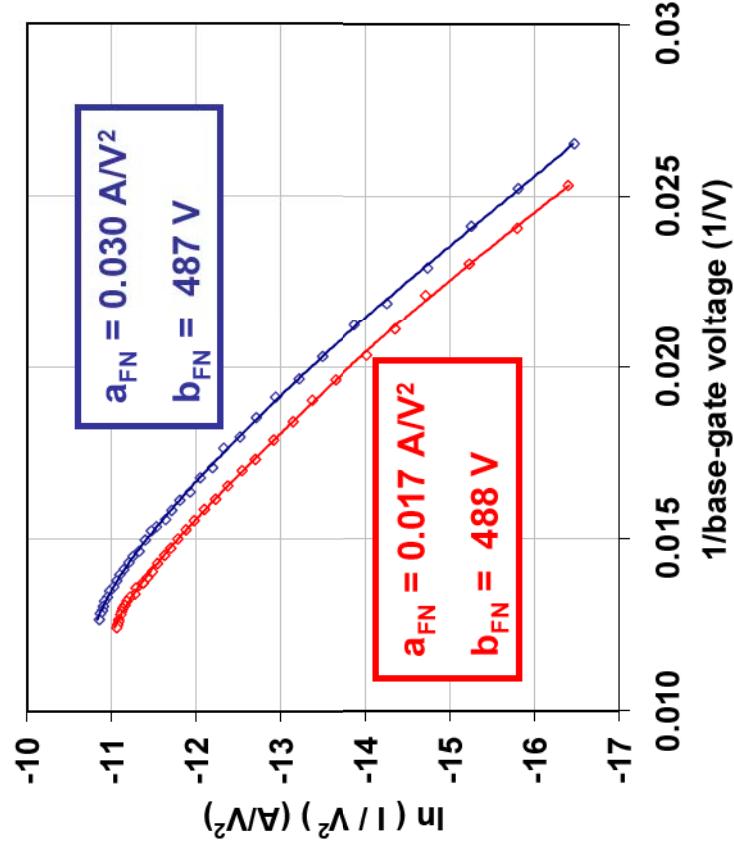
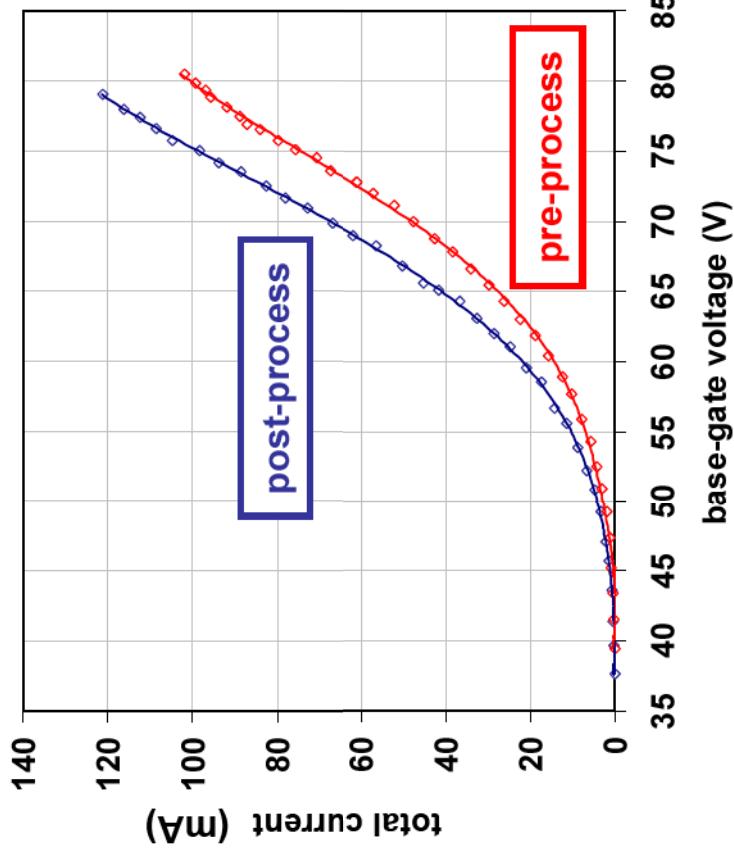
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High Duty Processing

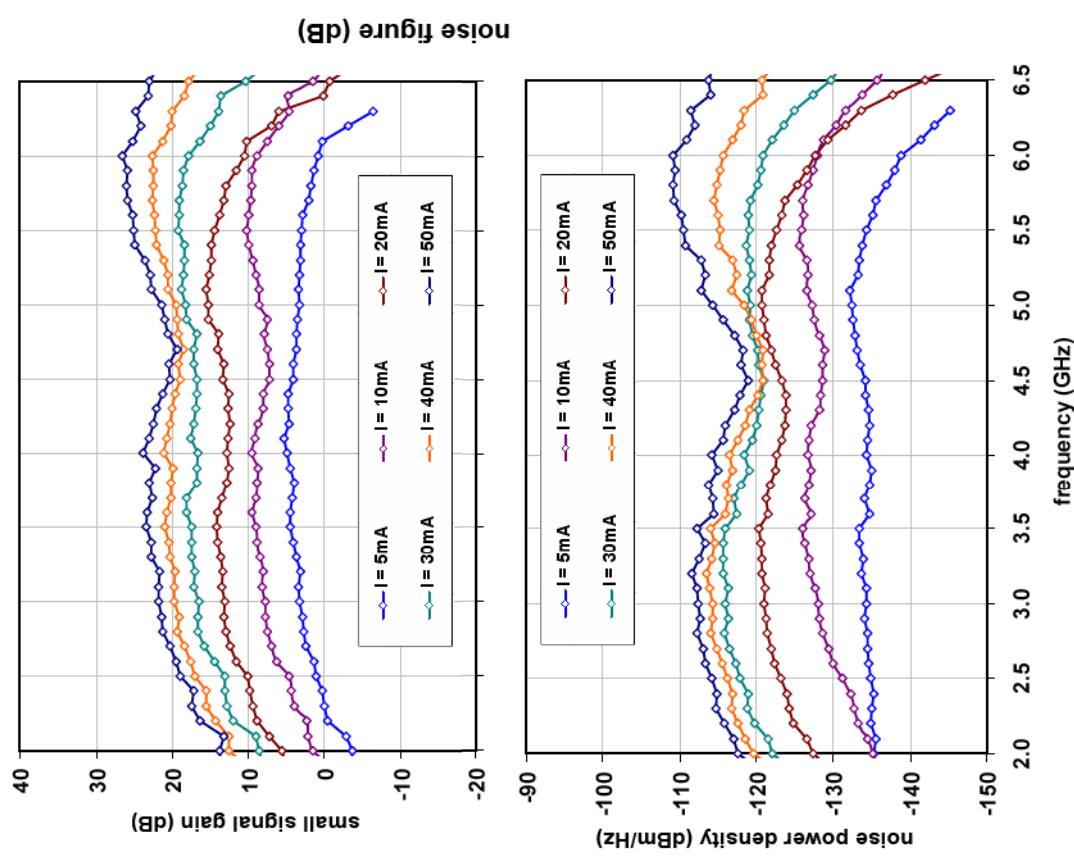


- High duty processing results in significant increase in a_{FN} , b_{FN} remains constant
 - Implies that the active area of the cathode is increasing, work function unchanged
 - Change appears to be permanent (time scale of weeks or longer)

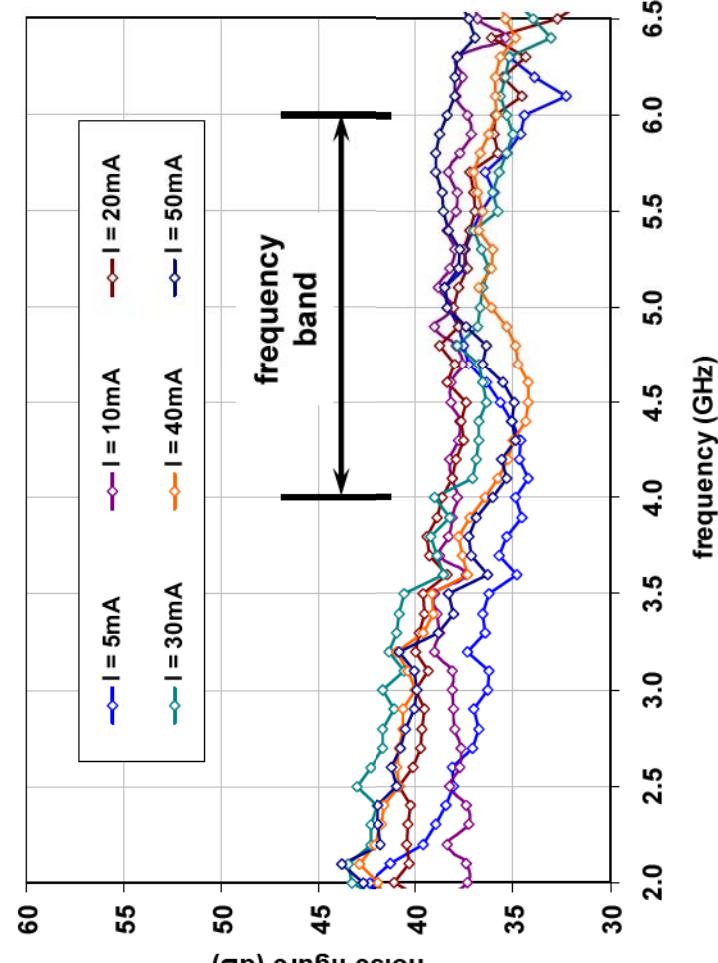
Experimental Results



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Noise Figure vs. Freq + Current



$$\text{NPD} = -174 \text{ dBm/Hz} + G \text{ (dB)} + \text{NF (dB)}$$

- In-band noise figure = 35-39 dB up to 50mA
- Improved method will replace thermal noise with calibrated noise source

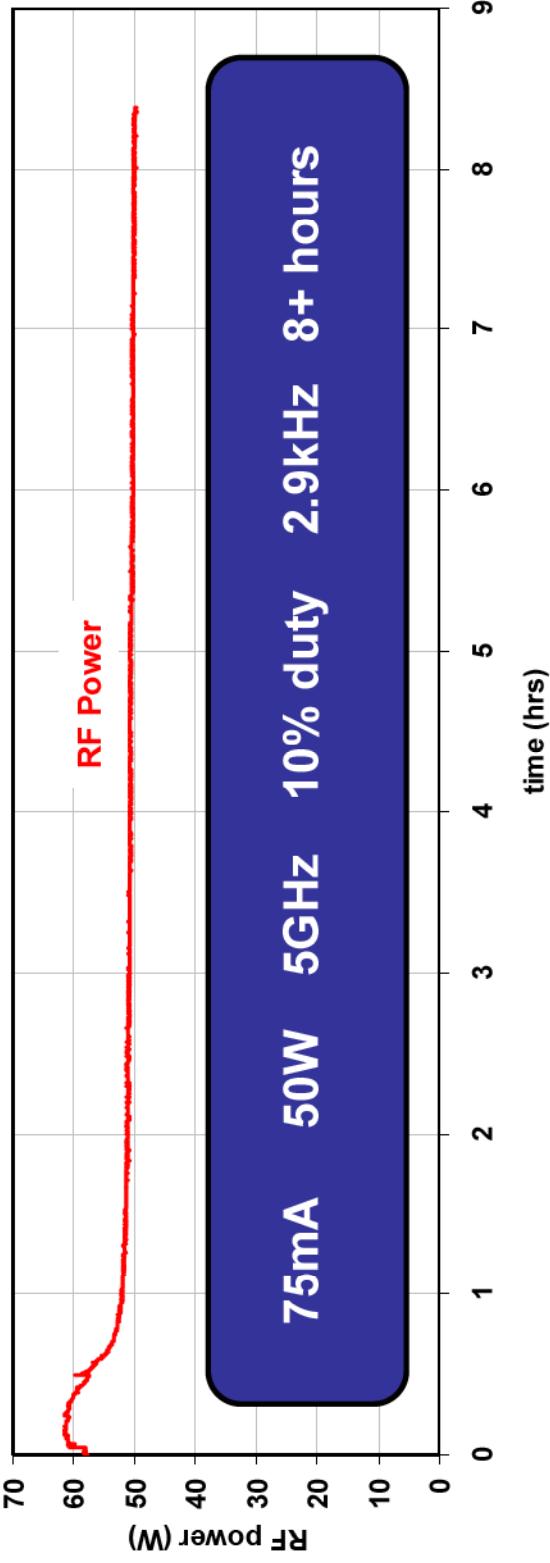
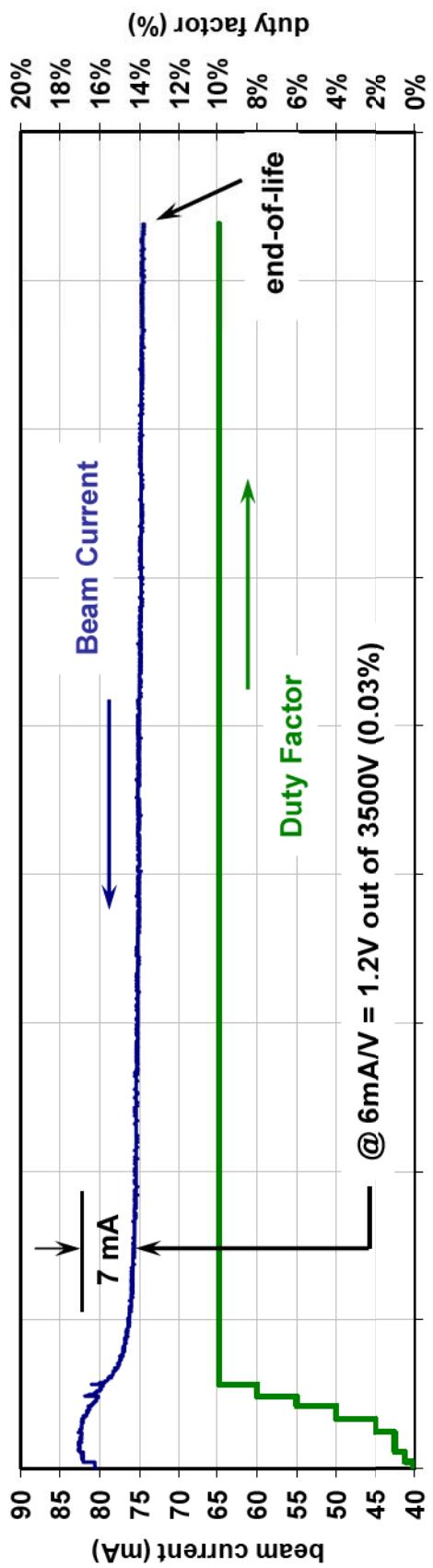
Experimental Results



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Operation at Max Average Current



Conclusions



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- Developed C-Band TWT specific for high current density field emitter array operation
- Demonstrated 72% cathode voltage reduction for full current operation
- Demonstrated TWT operation up to 120 mA, 15.4 A/cm², 100 W at 5GHz, 33dB ssg, 22dB sat gain, 24% circuit efficiency, 99% (97%) DC (RF) transmission
- Transconductance demonstrated at 8x that of legacy SRI FEA
- Life tests conducted up to 100 mA (12.7A/cm²) – 153 hrs total – 80mA at 10% duty highest average current
- Noise figure measured vs. current and frequency up to 50mA
- Time dependent changes in emission appear to be due to both cathode effective area increase and power supply variation with time
- Second cold cathode TWT built with modified operating characteristics for improved reliability

Acknowledgement



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